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## NTE1765 Integrated Circuit Dual Channel Current Mode Controller

### **Description:**

The NTE1765 is a high performance, fixed frequency, dual current mode controller in a 16-Lead DIP type package. This device is specifically designed for Off-Line and DC to DC converter applications offering the designer a cost effective solution with minimal external components. The NTE1765 features a unique oscillator for precise duty cycle limit and frequency control, a temperature compensated reference, two high gain error amplifiers, two current sensing comparators, drive output 2 enable pin, and two high current totem pole outputs ideally suited for driving power MOSFETS.

Also included are protective features consisting of input and reference undervoltage lockouts each with hysteresis, cycle-by-cycle current limiting, and a latch for single pulse metering of each output.

### **Features:**

- Unique Oscillator for Precise Duty Cycle Limit and Frequency Control
- Current Mode Operation to 500kHz
- Automatic Feed Forward Compensation
- Separate Latching PWMs for Cycle-By-Cycle Current Limiting
- Internally Trimmed Reference with Undervoltage Lockout
- Drive Output 2 Enable Pin
- Two High Current Totem Pole Outputs
- Input Undervoltage Lockout with Hysteresis
- Low Start-Up and Operating Current

### **Absolute Maximum Ratings:**

Total Power Supply Current, $I_{CC}$ .....	50mA
Zener Current, $I_Z$ .....	50mA
Output Current, Source or Sink (Note 1), $I_O$ .....	1A
Output Energy (Capacitive Load per Cycle), $W$ .....	5.0μJ
Current Sense, Enable and Voltage Feedback Inputs, $V_{in}$ .....	-0.3 to +5.5V
Sync Input, High State (Voltage), $V_{IH}$ .....	5.5V
Sync Input, Low State (Reverse Current), $I_{IL}$ .....	-5.0mA
Error Amp Output Sink Current, $I_O$ .....	10mA
Maximum Power Dissipation ( $T_A = +25^\circ\text{C}$ ), $P_D$ .....	1.25mW
Thermal Resistance, Junction-to-Ambient, $R_{thJA}$ .....	100°C/W
Operating Junction Temperature, $T_J$ .....	+150°C
Operating Ambient Temperature Range, $T_A$ .....	0° to +70°C
Storage Temperature Range, $T_{stg}$ .....	-65° to +150°C

Note 1. Maximum package power dissipation limits must be observed.

**Electrical Characteristics:** ( $V_{CC} = 15V$  (Note 2),  $R_T = 8.2k\Omega$ ,  $C_T = 3.3nF$ , Note 3 unless otherwise specified)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
<b>Reference Section</b>						
Reference Output Voltage	$V_{ref}$	$I_O = 1mA$ , $T_J = +25^\circ C$	4.9	5.0	5.1	V
Line Regulation	$Reg_{line}$	$V_{CC} = 11V$ to $15V$	–	2.0	20	mV
Load Regulation	$Reg_{load}$	$I_O = 1mA$ to $10mA$	–	3.0	25	mV
Total Output Variation over Line, Load and Temperature	$V_{ref}$		4.85	–	5.15	V
Output Short Circuit Current	$I_{SC}$		30	100	–	mA
<b>Oscillator and PWM Sections</b>						
Total Frequency Variation over Line and Temperature	$f_{OSC}$	$V_{CC} = 11V$ to $15V$ , $T_A = 0^\circ$ to $+70^\circ C$	46.5	49.0	51.5	kHz
Frequency Change with Voltage	$\Delta f_{OSC}/\Delta V$	$V_{CC} = 11V$ to $15V$	–	0.2	1.0	%
Duty Cycle at each Output	Maximum		46.0	49.5	52.0	%
	Minimum		–	–	0	%
Sync Input Current						
High State	$I_{IH}$	$V_{in} = 2.4V$	–	170	250	$\mu A$
Low State	$I_{IL}$	$V_{in} = 0.8V$	–	80	160	$\mu A$
<b>Error Amplifiers</b>						
Voltage Feedback Input	$V_{FB}$	$V_O = 2.5V$	2.42	2.50	2.58	V
Input Bias Current	$I_{IB}$	$V_{FB} = 5V$	–	–0.1	–1.0	$\mu A$
Open–Loop Voltage Gain	$A_{VOL}$	$V_O = 2V$ to $4V$	65	100	–	dB
Unity Gain Bandwidth	BW	$T_J = +25^\circ C$	0.7	1.0	–	MHz
Power Supply Rejection Ratio	PSRR	$V_{CC} = 11V$ to $15V$	60	90	–	dB
Output Current Source			–0.45	–	–	mA
		$V_O = 3V$ , $V_{FB} = 2.3V$	2.0	–1.0	–	mA
Sink	$I_{Sink}$	$V_O = 1.2V$ , $V_{FB} = 2.7V$	–	12	–	mA
Output Voltage Swing						
High State	$V_{OH}$	$R_L = 15k$ to GND, $V_{FB} = 2.3V$	5.0	6.2	–	V
Low State	$V_{OL}$	$R_L = 15k$ to $V_{ref}$ , $V_{FB} = 2.7V$	–	0.8	1.1	V
<b>Current Sense Section</b>						
Current Sense Input Voltage Gain	$A_V$	Note 4, Note 5	2.75	3.00	3.25	V/V
Max. Current Sense Input Threshold	$V_{th}$	Note 4	430	480	530	mV
Input Bias Current	$I_{IB}$		–	–2	–10	$\mu A$
Propagation Delay (Current Sense Input to Output)	$t_{PLN(IN/OUT)}$		–	150	300	ns

**Note 2.** Adjust  $V_{CC}$  above the Start–Up threshold before setting to 15V.

**Note 3.** For typical values,  $T_A = +25^\circ C$ ; for Min/Max values,  $T_A = 0^\circ$  to  $+70^\circ C$ . Low duty cycle pulse techniques are used during test to maintain junction temperature as close to ambient as possible.

**Note 4.** This parameter is measured at the latch trip point with  $V_{fb} = 0V$ .

**Note 5.** Comparator gain is defined as  $A_V = \frac{\Delta V \text{ Compensation}}{\Delta V \text{ Current Sense}}$

**Electrical Characteristics (Cont'd):** ( $V_{CC} = 15V$  (Note 2),  $R_T = 8.2k\Omega$ ,  $C_T = 3.3nF$ , Note 3 unless otherwise specified)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
<b>Drive Output 2 Enable Pin</b>						
Enable Pin Voltage High State	$V_{IH}$	Output 2 Enabled	3.5	–	$V_{ref}$	V
Low State	$V_{IL}$	Output 2 Disabled	0	–	1.5	V
Low State Input Current	$I_{IB}$	$V_{IL} = 0V$	100	250	400	$\mu A$
<b>Drive Outputs</b>						
Output Voltage Low State	$V_{OL}$	$I_{Sink} = 20mA$	–	0.1	0.4	V
		$I_{Sink} = 200mA$	–	1.6	2.5	V
High State	$V_{OH}$	$I_{Source} = 20mA$	13.0	13.5	–	V
		$I_{Source} = 200mA$	12.0	13.4	–	V
Output Voltage with UVLO Activated	$V_{OL(UVLO)}$	$V_{CC} = 6V, I_{Sink} = 1mA$	–	0.1	1.1	V
Output Voltage Rise Time	$t_r$	$C_L = 1nF$	–	28	150	ns
Output Voltage Fall Time	$t_f$	$C_L = 1nF$	–	25	150	ns
<b>Undervoltage Lockout Section</b>						
Start-Up Threshold	$V_{th}$		13	14	15	V
Min. Operating Voltage After Turn-On	$V_{CC(min)}$		9.0	10.0	11.0	V
<b>Total Device</b>						
Power Supply Current Start-Up	$I_{CC}$	$V_{CC} = 12V$	–	0.6	1.0	mA
		Note 2	–	20	25	mA
Operating						
Power Supply Zener Voltage	$V_Z$	$I_{CC} = 30mA$	15.5	17.0	19.0	V

**Note 2.** Adjust  $V_{CC}$  above the Start-Up threshold before setting to 15V.

**Note 3.** For typical values,  $T_A = +25^\circ C$ ; for Min/Max values,  $T_A = 0^\circ$  to  $+70^\circ C$ . Low duty cycle pulse techniques are used during test to maintain junction temperature as close to ambient as possible.



